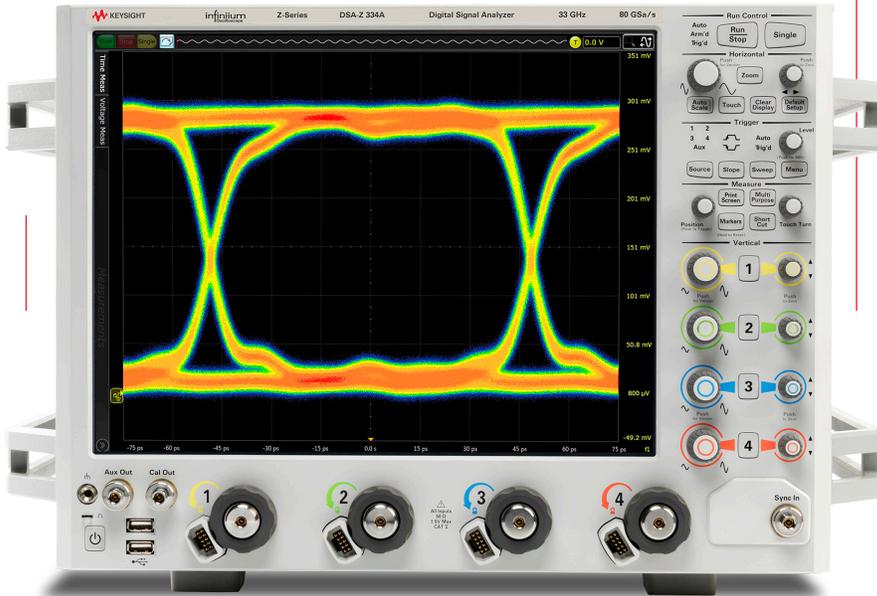


Keysight Technologies

N5393D PCI Express 3.0 (Gen3) Software for Infiniium Oscilloscopes

Data Sheet



Verify and debug your PCI Express® designs more easily

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Keysight Technologies, Inc. PCI Express electrical performance validation and compliance software provides you with a fast and easy way to verify and debug your PCI Express 3.0, 2.0, and 1.1/1.0a designs for both silicon validation (as per the PCIe® BASE specification) as well as for add-in cards and motherboard systems (as per the PCIe CEM specification).

The PCI Express electrical test software allows you to automatically execute PCI Express electrical transmitter tests, and it displays the results in a flexible report format. In addition to the measurement data, the report provides a margin analysis that shows how closely your device passed or failed each test.

The PCI Express electrical test software utilizes the prescribed test methods and algorithms as required by the PCI Express Card Electromechanical (CEM) specifications for all current PCI Express Standards. This produces results that are not only consistent with the PCI-SIG® SigTest utility, but also provides you with a fast and easy means of executing complex two-port motherboard tests and single port add-in card test with total automation.

In addition to transmitter testing, the PCI Express electrical test software also provides an optional receiver test calibration test suite, which allows you to setup your N4903B JBERT bit error ratio tester for performing PCI Express 3.0 jitter tolerance testing under the PCIe 3.0 BASE specification.

The PCI Express electrical performance validation and compliance software performs a wide range of electrical tests as per the PCI Express PCI Express 2.0 and 1.1/1.0a. electrical specifications for add-in cards and motherboard systems as documented in Section 4 of the base specification and Section 4 of the card electromechanical specification.

Tests for PCI Express 3.0 (based on section 4.3.3.10 and 4.3.3.13) are also included to help you test your products against for the next generation of this powerful I/O technology.

In addition to full swing (800 mV) testing, the software also supports testing for low-power, half-swing devices (400 mV) as per the PCI Express Architecture Mobile Graphics Low-Power Addendum to the PCI Express Base Specification Revision 1.0.

Features

The PCI Express electrical test software offers several features to simplify the validation of PCI Express designs:

- PCIe 3.0 measurements for uncorrelated TJ, DJ, and PWJ, pseudo package loss, and pre-set de-emphasis and preshoot.
- Automated 1.6 M Unit Interval (or greater) testing for highest accuracy when embedding PCIe reference channel and package model losses
- Results consistent with PCI-SIG SigTest software utility
- Support for de-embedding of test fixtures and cables*
- Test setup wizard for ease-of-use
- Wide range of electrical transmitter and reference clock tests
- PCI-SIG SigTest clock recovery algorithm
- Optional integrated receiver test calibration suite for automated calibration (BASE spec) of your N4903B JBERT**
- Automated scope measurement setup
- Test results report generation
- Pass/fail margin analysis
- Reference clock phase jitter analysis
- Two-port (explicit clock and data) supported for motherboard signal quality testing
- Support for both full-swing and low-power, half-swing devices.

*Requires the purchase of the optional Keysight InfiniiSim Waveform Transformation Toolset for Infiniium Oscilloscopes

** Requires the purchase of N5393D-4FP software license. Receiver test hardware and fixtures not included and must be purchased separately

With the PCI Express electrical test software, you can use the same oscilloscope you use for everyday debugging to perform automated testing and margin analysis based on the PCI-SIG-specified tests.

PCI Express compliance testing

To pass signal quality testing at a PCI-SIG-sponsored compliance workshop, your product must successfully pass “Gold Suite” testing, based on the PCI-SIG SigTest application. The SigTest application tests your device against the minimum signal-quality performance requirements for PCI. If you are developing receivers and transmitters for add-in boards and system motherboards, the PCI Express electrical test software helps you execute the SigTest tests and additional oscilloscope already completed tests. See the list of tests in Table 3 on page 16 (for 1.1 test coverage).

While SigTest tests provide a good overview of PCI Express electrical signal quality, they address only a small subset of the electrical compliance measurements specified in the PCI-SIG specification. The SigTest application also provides minimal reporting capability with pass/fail indication and measurement values, and has limited debugging capabilities to decipher eye mask violations or excessive jitter.

For PCI Express 3.0 measurements, the software automatically calculates uncorrelated total jitter, uncorrelated deterministic jitter, uncorrelated PWJ necessary for validating new PCIe 3.0 compliant chipsets. For versions of devices compliant with PCI Express 2.0 or earlier, random jitter is also reported for completeness and a voltage margin “eye” diagram is included in the final HTML report. DJ and TJ values are specified in the PCIe 2.0 specification and are required for compliance verification.



Figure 1. PCI Express 2.0 supports data rates up to 5.0 GT/s as shown above (-3.5 dB de-emphasis)

Benefits

PCI Express electrical test software benefits

The PCI Express electrical test software saves you time by setting the stage for automatic execution of PCI Express electrical tests, including JBERT jitter stress calibration (optional). Part of the difficulty of performing electrical tests for PCI Express is hooking up the oscilloscope, loading the proper setup files, and then analyzing the measured results by comparing them to limits published in the specification. The PCI Express electrical test software does much of this work for you. In addition, if you discover a problem with your device, robust debug tools are available to aid in root-cause analysis. These debug tools are provided by the Keysight E2688A high-speed serial data analysis software, which you must install on your oscilloscope to use the PCI Express electrical test software.

The software also now has an integrated interface for controlling the InfiniiSim Waveform Transformation Toolset for de-embedding of test fixtures. Introduced with PCIe 2.0, de-embedding of test fixtures utilizes S-parameters as input to create a de-embed model that helps to restore high frequency signal content that is often lost or significantly attenuated by test fixtures and cables. This can help to recover significant jitter margin normally lost to fixtures used in a test setup.

The software can be purchased with an optional test suite for performing the calibration of your Keysight JBERT (B) bit error ratio tester for stressed eye receiver testing for PCIe 3.0 silicon. This helps ensure consistent run-to-run setup of the instrumentation, saving you time and providing consistent and accurate receive test results.

The PCI Express electrical test software offers many more electrical tests than the SigTest application. Unlike the SigTest application, the PCI Express electrical test software automatically configures the oscilloscope for each test, and it provides an informative results report that includes margin analysis indicating how close your product is to passing or failing a particular test assertion. Table 1 shows a side-by-side comparison of the capabilities of the SigTest application and the Keysight PCI Express electrical test software. A list of the measurements made by the PCI Express electrical test software can be found in Table 3, (Table 3 contains comparison of SigTest vs. Keysight).

Table 1. Comparison of capabilities of the Keysight PCI Express electrical test software and the PCI-SIG SigTest application.

| Capability | Keysight PCI Express software | PCI-SIG SigTest |
|---|---|-------------------------------|
| Support for PCIe 3.0 | BASE Spec | N/A |
| Integrated de-embedding support | Yes (InfiniiSim waveform transformation toolset required) | No |
| Number of measurement assertions | 16+ | 4 |
| Support for PCIe 1.0a, 1.1, 2.0 | Yes | Yes |
| Reference clock tests | 10 (1.1) | 0* |
| Automated oscilloscope setup for each measurement | Yes, guided | No, single setup |
| Measurement results | Pass/fail with margin analysis | Pass/fail with measured value |
| CEM based measurement methodology | Yes | Yes |
| Clock recovery method | PCI-SIG SigTest or 1st/2nd order PLL | PCI-SIG SigTest |
| Brick wall filter (2.0 testing) | Yes | Yes |
| Custom HTML report generation | Yes | No |
| Support for low power device | Yes | No |
| Selectable number of tests performed | Yes | No |
| Multi-trial run support | Yes | No |
| Debug mode for "what if" analysis | Yes | No |
| Compliance test boards supported | CBB1, CBB2, CLB1, CLB2 | CBB1, CBB2, CLB1, CLB2 |

*PCI-Sig offers a separate utility (Clock_Jitter) for analyzing reference clock phase jitter.

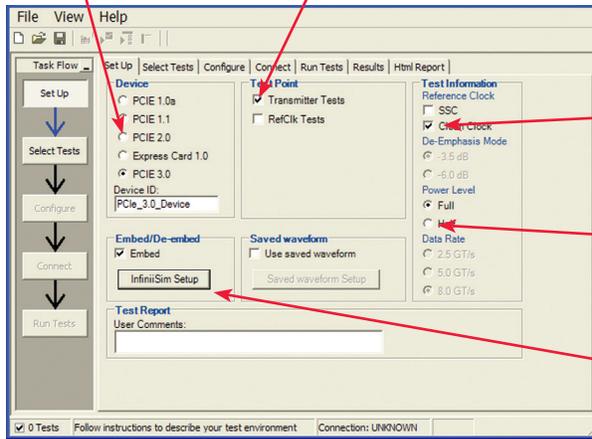
Easy Test Definition

The PCI Express electrical test software extends the ease-of-use advantages of Keysight's Infiniium oscilloscopes to testing PCI Express designs. The Keysight automated test engine walks you quickly through the steps required to define the tests, set up the tests, perform the tests, and view the test results. You can select a category of tests all at once, or specify individual tests. You can save tests and configurations as project files and recall them later for quick testing and review of previous test results. Straightforward menus let you perform tests with a minimum of mouse clicks.

The software allows you to easily specify the test standard you want to use to test the compliance of your device. This makes test setup easy as only the appropriate tests for the test point you pick are shown on later test selection pages.

Pick the standard you want to test against

Choose the test point or specific signal you want to test



Test with SSC enabled or with a clean clock (for compliance)

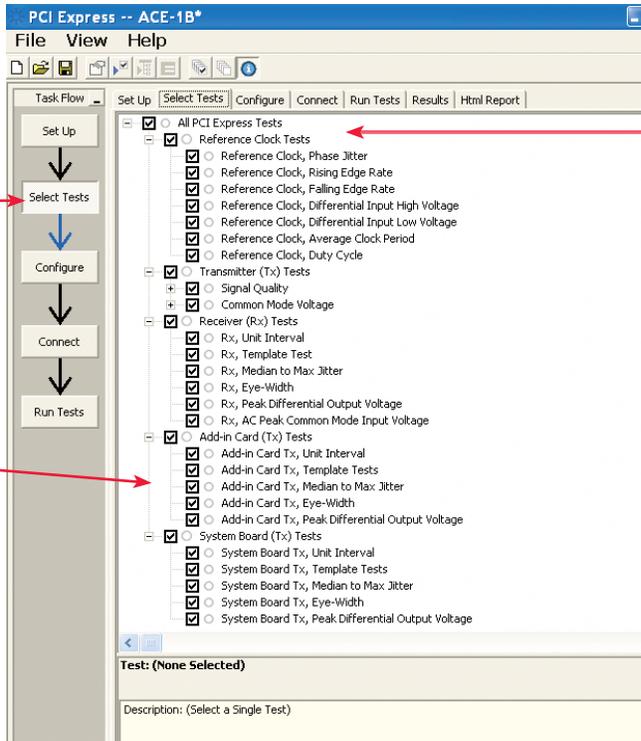
Choose half swing if testing low power devices

De-embed test fixtures with the optional InfiniiSim waveform transformation toolset

Figure 2. The software allows you to easily specify the test standard you want to use to test the compliance of your device. This makes test setup easy as only the appropriate tests for the test point you pick are shown on later test selection pages.

Easy to follow task flow for configuring and running tests

Select one test or a group of tests with a single mouse click



Test your reference clock for phase jitter to help ensure clean high data rate transmissions

Figure 3. The Keysight automated test engine guides you quickly through selecting tests, configuring tests, setting up the connection, running the tests, and viewing the results. Individual tests or groups of tests are easily selected with a mouse click.

PCI Express 3.0

The N5393D includes support for testing PCI Express 3.0 devices. The tests supported include new jitter, voltage, de-emphasis, preshoot, pseudo S21 loss and others defined by the PCI Express 3.0 BASE specification. In addition, with the addition of the optional InfiniiSim Waveform Transformation Toolset, the N5393D also integrates de-embedding of test channel and cable losses with user-supplied S-parameters for fixtures and connectors. De-embedding is used to recover jitter losses due to the attenuation of high frequency elements caused by the test channel.

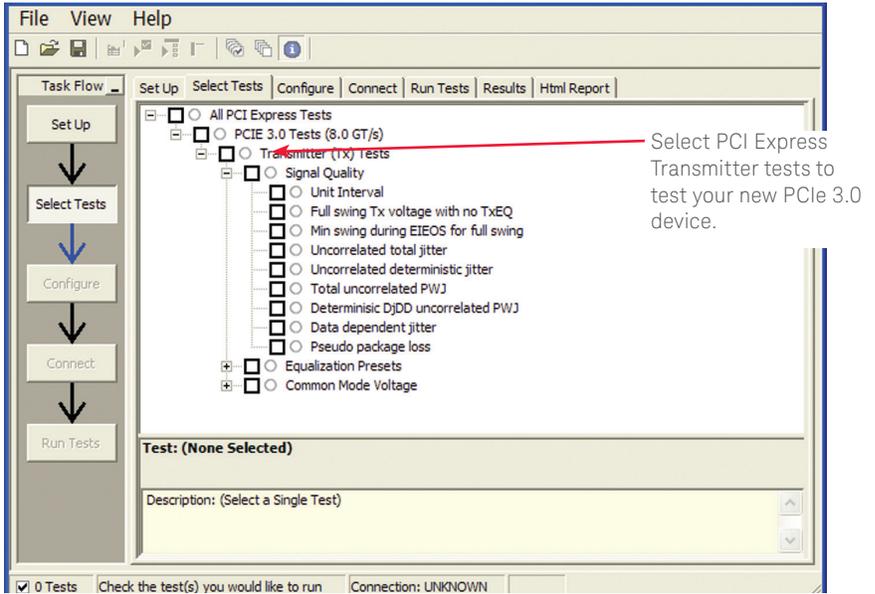


Figure 4. PCI Express 3.0 transmitter tests

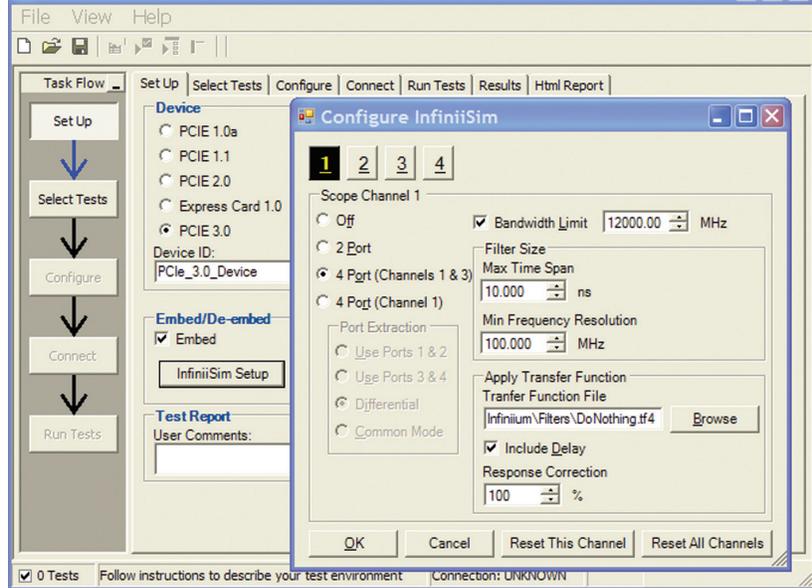
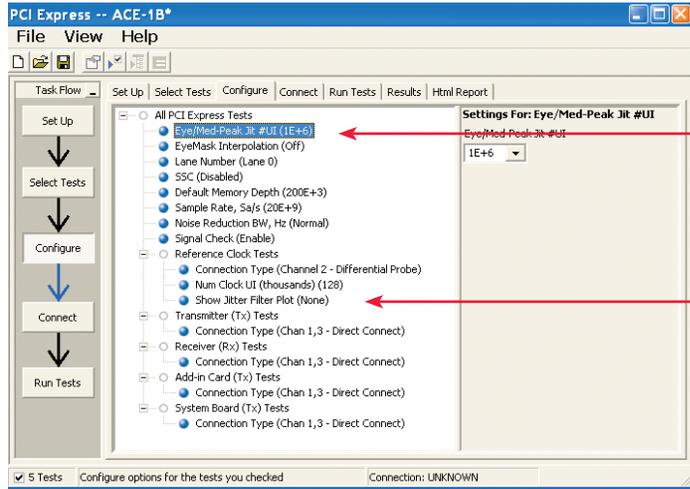


Figure 5. The N5393D integrates de-embedding capability when coupled with the optional InfiniiSim waveform transformation toolset

Configurability and Guided Connections

The PCI Express electrical test software provides flexibility in your test setup. It guides you to make connection changes with hookup diagrams when the tests you select require it. All PCI Express electrical compliance tests you perform are based on the official PCI-SIG approved set of test fixtures. The compliance fixtures include the Compliance Base Board (CBB2) for add-in card testing, and the Compliance Load Board (CLB2) for motherboard or system testing. Connection to the compliance test fixtures is selectable between SMA/SMP cables or Keysight InfiniiMax active differential probes.



Specify 1 million UI (or more) for your jitter measurements

Show the spectral response of your reference clock in the critical 1.5 - 22-MHz region

Figure 6. In configuring the tests, you specify the device to test, its configuration, and how the oscilloscope is connected.

If more than one test setup connection is required, you will be notified here

You are prompted to make the appropriate connections for the set of tests

Toggle circuit to switch between Gen1 (2.5 GBit/s) and Gen2 (50 GBit/s)

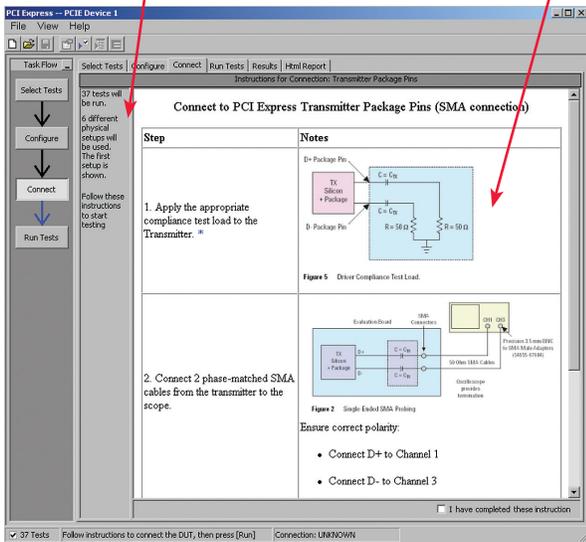


Figure 7. When you make multiple tests where the connections must be changed, you are prompted with connection diagrams and/or photographs.

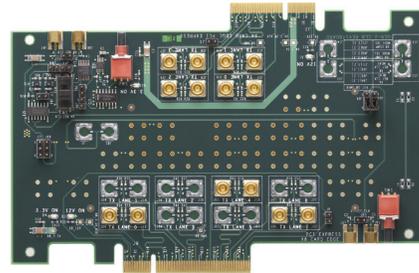
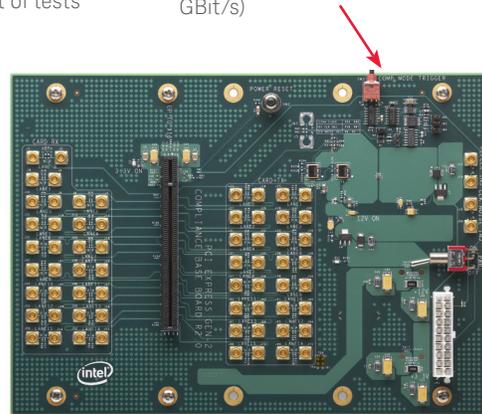


Figure 8. The PCI-SIG Compliance Base Board (CBB2) for Gen2 add-in card testing, and the Compliance Load Board (CLB2) for Gen2 motherboard or host system testing.

Reports with Margin Analysis

In addition to providing you with measurement results, the PCI Express electrical test software provides a report format that shows you not only where your product passes or fails, but also reports how close you are to the limits specified for a particular test assertion. You can select the margin test report parameter, which means you can specify the level at which warnings are issued to alert you to electrical tests where your product is operating close to the official test limit defined by the PCI Express 2.0, 1.0a or 1.1 specifications.

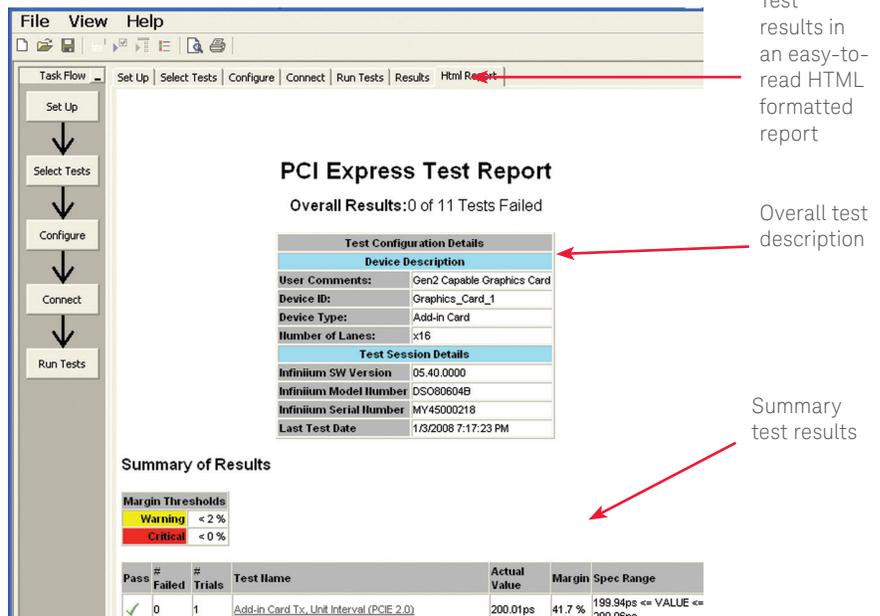


Figure 9. The PCI Express electrical test software results report documents your test, indicates the pass/fail status, the test specification range, the measured values, and shows how much margin you have.

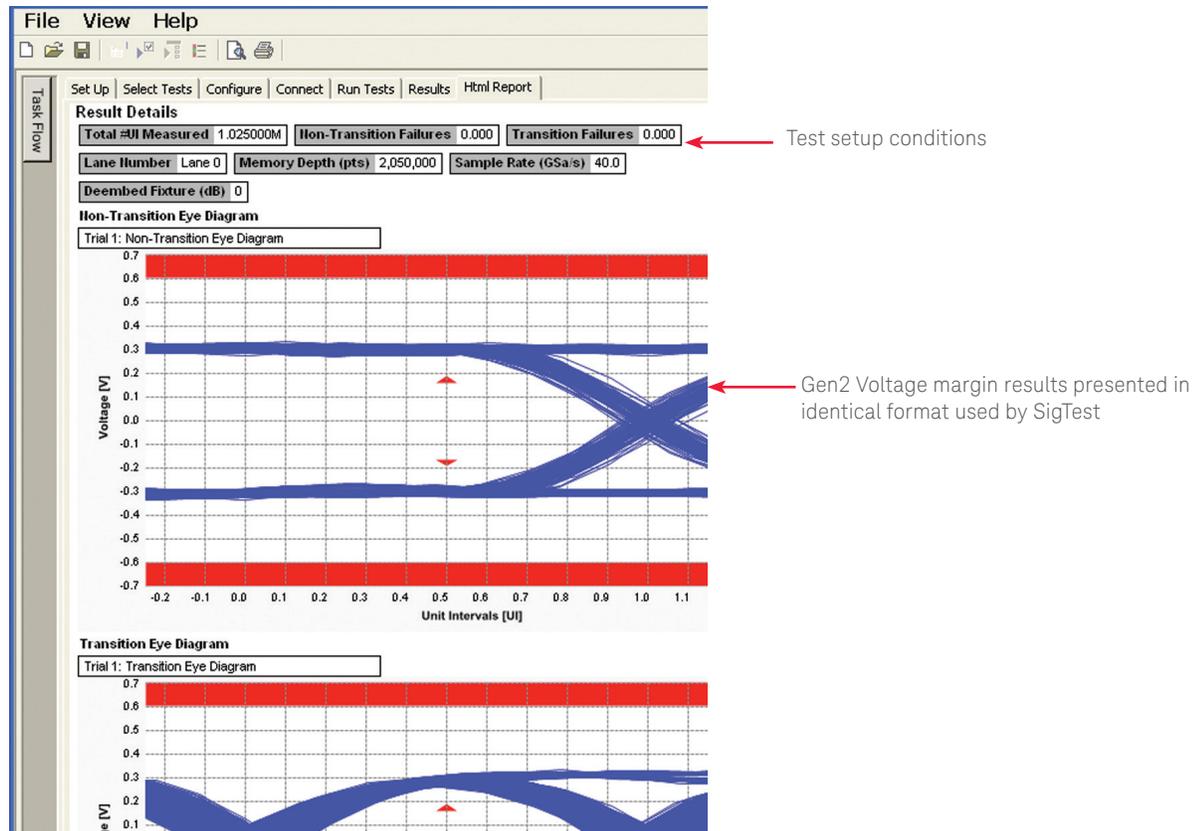


Figure 10. The HTML report provides additional details including test setup conditions, graphical results, and test limits (where appropriate).

Reports with Margin Analysis (continued)

The screenshot shows the 'PCI Express Test Report' window. The overall result is 'FAIL (1 of 16 Tests Failed)'. The 'Test Configuration Details' table includes:

| | |
|----------------------|----------------------|
| User Comments | |
| Device Type | |
| Device ID | Device 1 |
| Number of Lanes | |
| Last Test Date | 5/28/2004 2:16:37 PM |
| Model Number | 54855A |
| Serial Number | No Serial |
| Infiniium SW Version | 03.49.5002R |

The 'Summary of Results' section includes 'Margin Thresholds':

- Warning <= 15 %
- Critical <= 0 %

The main results table is as follows:

| Pass | Test Name | Spec Range | Measured Value | Margin |
|------|---|------------------------|----------------|---------|
| ✓ | System Board Tx, Unit Interval | [399.88ps to 400.12ps] | 399.97ps | 37.1 % |
| ✓ | System Board Tx, Template Tests | Zero Mask Failures | 0 | N/A |
| ✓ | System Board Tx, Median to Max Jitter | <= 108.50ps | 52.50ps | 51.6 % |
| ✓ | System Board Tx, Eye-Width | >= 183.00ps | 315.01ps | 72.1 % |
| ✓ | System Board Tx, Peak Differential Output voltage | [0.2530V to 1.2000V] | 0.9200V | 29.6 % |
| ✓ | Tx, Unit Interval | [399.88ps to 400.12ps] | 400.05ps | 29.6 % |
| ✓ | Tx, Template Tests | Zero Mask Failures | 0 | N/A |
| ✓ | Tx, Median to Max Jitter | <= 60.00ps | 48.80ps | 18.7 % |
| ✓ | Tx, Eye-Width | >= 0.700UI | 0.794UI | 13.4 % |
| ✓ | Tx, Peak Differential Output voltage | [0.8000V to 1.2000V] | 0.9372V | 34.3 % |
| ✓ | Tx, Rise/Falltime | >= 50.00ps | 205.47ps | 310.9 % |
| ✗ | Tx, Deemphasized Voltage Ratio | [-4.0dB to -3.0dB] | -2.7dB | 28.8 % |
| ✓ | Tx, RMS AC Peak Common Mode Output Voltage | <= 20.0mV | 16.1mV | 19.5 % |
| ✓ | Tx, Avg DC Common Mode Output Voltage | [0.0000V to 3.6000V] | 1.0380V | 26.8 % |
| ✓ | Tx, DC Common Mode Output Voltage Variation | <= 100.0mV | -42.5mV | 57.5 % |
| ✓ | Tx, DC Common Mode Line Delta | <= 25.0mV | 0.3mV | 98.8 % |

User set margin thresholds for warning and failure indicators

Margin values indicate when the results are approaching test limits. Warnings and failures are highlighted.

Figure 11. How close you are to passing or failing a test is indicated as a % in the margin field. A result highlighted in yellow or red indicates that the margin threshold level for a warning or failure was detected.

Extensibility

You may add additional custom tests or steps to your application using the User Defined Application (UDA) development tool (www.keysight.com/find/uda). Use UDA to develop functional “Add-Ins” that you can plug into your application.

Add-ins may be designed as:

- Complete custom tests (with configuration variables and connection prompts)
- Any custom steps such as pre or post processing scripts, external instrument control and your own device control

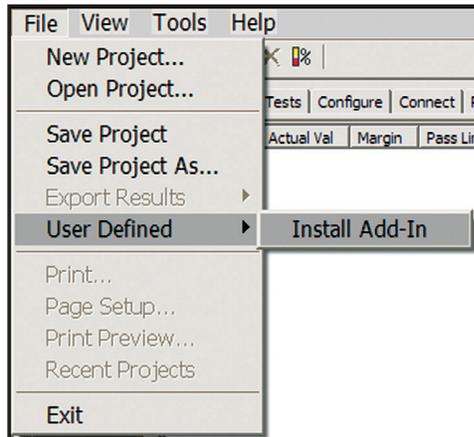


Figure 12. Importing a UDA Add-In into your test application.

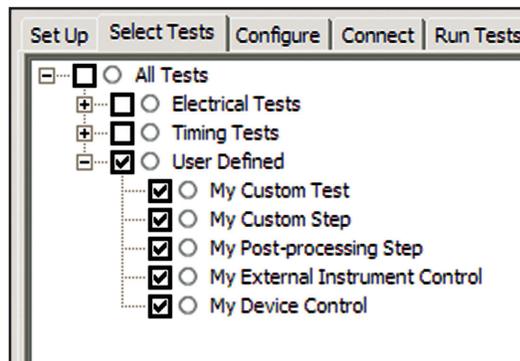


Figure 13. UDA Add-In tests and utilities in your test application.

Automation

You can completely automate execution of your application's tests and Add-Ins from a separate PC using the included N5452A Remote Interface feature (download free toolkit from www.keysight.com/find/scope-apps-sw). You can even create and execute automation scripts right inside the application using a convenient built-in client.

The commands required for each task may be created using a command wizard or from "remote hints" accessible throughout the user interface.

Using automation, you can accelerate complex testing scenarios and even automate manual tasks such as:

- Opening projects, executing tests and saving results
- Executing tests repeatedly while changing configurations
- Sending commands to external instruments
- Executing tests out of order

Combine the power of built-in automation and extensibility to transform your application into a complete test suite executive:

- Interact with your device controller to place it into desired states or test modes before test execution.
- Configure additional instruments used in your test suite such as a pattern generator and probe switch matrix.
- Export data generated by your tests and post-process it using your favorite environment, such as MATLAB, Python, LabVIEW, C, C++, Visual Basic etc.
- Sequence or repeat the tests and "Add-In" custom steps execution in any order for complete test coverage of the test plan.

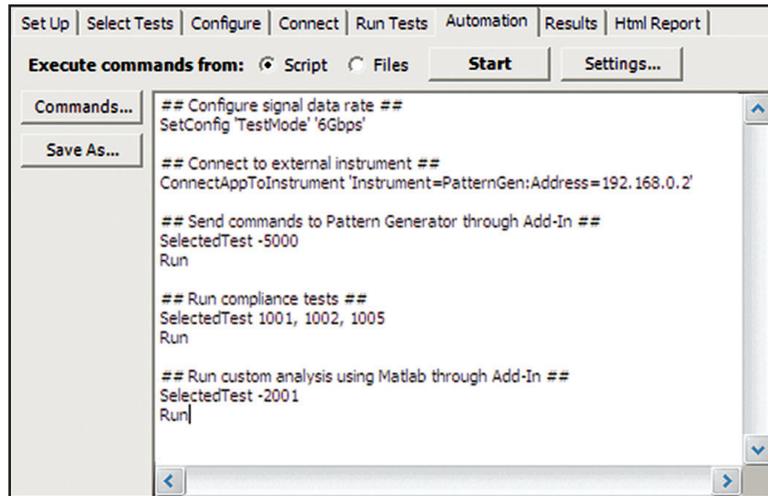


Figure 14. Remote Programming script in the Automation tab.

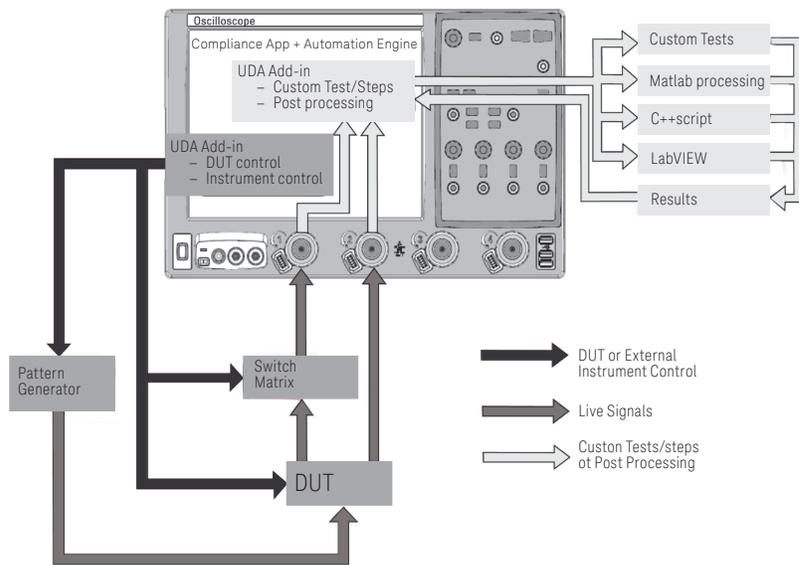


Figure 15. Combine the power of built-in automation and extensibility to transform your application into a complete test suite executive.

Switch Matrix

The Keysight N5393D Option 7FP switch matrix software tool for the PCI Express compliance application, used together with switch matrix hardware, enables fully automated testing for this multi-lane digital bus interface. The benefits of this automated switching solution include:

- Eliminate reconnections, which saves time and reduces errors through automating test setup for each lane of a multi-lane bus.
- Maintain accuracy with the use of unique N2809A Precision-Probe or InfiniiSim features to compensate for switch path losses and skew.
- Customize testing by using remote programming interface and the user-defined application tool for device control, instrument control and test customization.

More information of the switching solution and configuration, visit <http://literature.cdn.keysight.com/find/switching> and the Keysight application note with the publication number 5991-2375EN.



Figure 16. Automated testing for multi-lane digital bus interface through switching solution

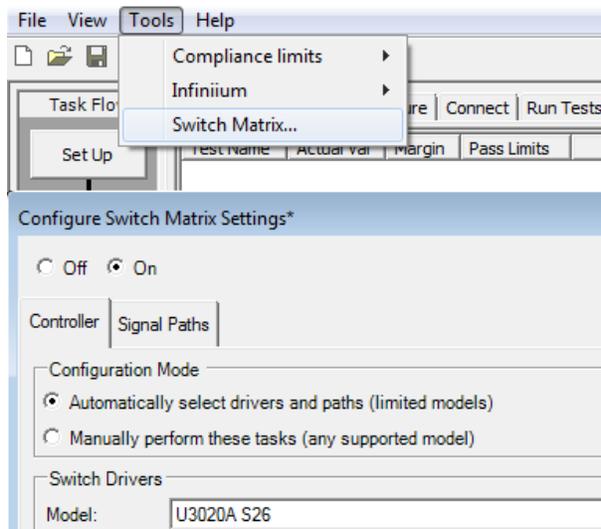


Figure 17. Switch matrix software feature enabled in the compliance application

Receiver Stressed Eye Calibration

The PCI Express 3.0 BASE specification outlines the requirements for a PCIe 3.0 compliant receiver equalizer. The capabilities defined employ a reference equalizer that consists of a CTLE (continuous time linear equalizer) and a single tap DFE (decision feedback equalizer).

In order to ensure that your devices receiver equalizer is at least as capable as the reference equalizer defined in the PCIe 3.0 BASE specification, it is necessary to execute a stressed eye receiver test. The signal that must be presented to the receiver must represent a worst case condition yet still be a valid and compliant PCIe 3.0 signal.

To achieve this calibrated worst case signal, it is necessary to carefully construct a significantly small amplitude signal that contains a prescribed amount of certain specified impairments. These impairments include sinusoidal jitter, random jitter, and channel induced intersymbol interference (ISI). In addition, it is necessary to add common mode and differential mode noise simultaneously to the jitter cocktail in order to emulate system crosstalk.

The N5393D-4FP along with your N4903B JBERT bit error ratio tester and required accessories, such as an 81150A Pulse Function Arbitrary Noise Generator, N4916B De-emphasis Signal Converter, and N4915A-014 PCI Express 3.0 calibration channels.

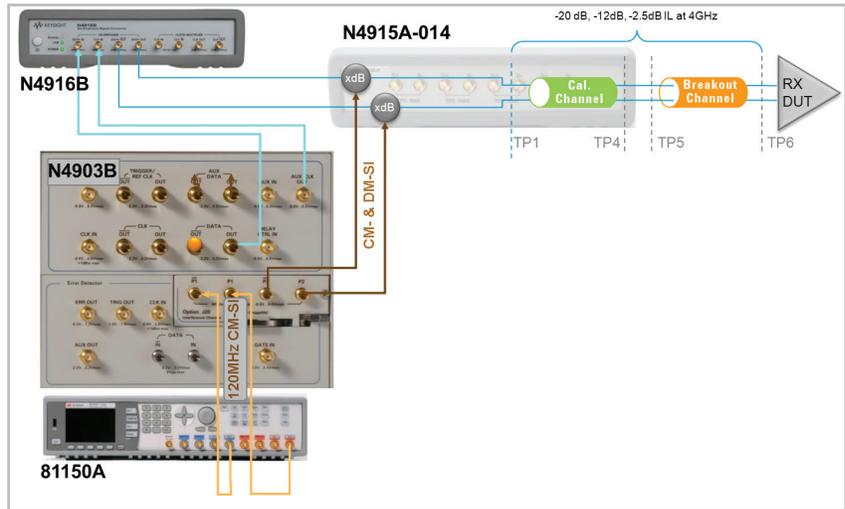


Figure 18. N4903B JBERT Setup for PCIe 3.0 Receiver Stress Testing.

Set target stressed voltage test parameters for the calibration

Set target stressed jitter test parameters for the calibration

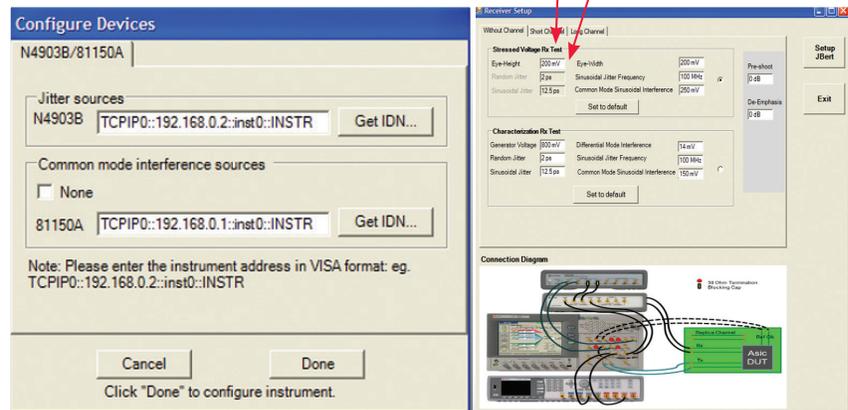


Figure 19. Setting up instrument control of the N4903B and 81150A from the PCIe application.

Receiver Stressed Eye Calibration (continued)

The N5393D utilizes the PCI SIG's own Seasim simulation software to determine the target signal impairments and communicates those parameters to the instruments configured as part of the receiver test setup. The Keysight DSA90000 series oscilloscope is used to capture traces from the JBERT system setup, and that information is used by Seasim to set the calibration values of the bit error ratio tester setup.

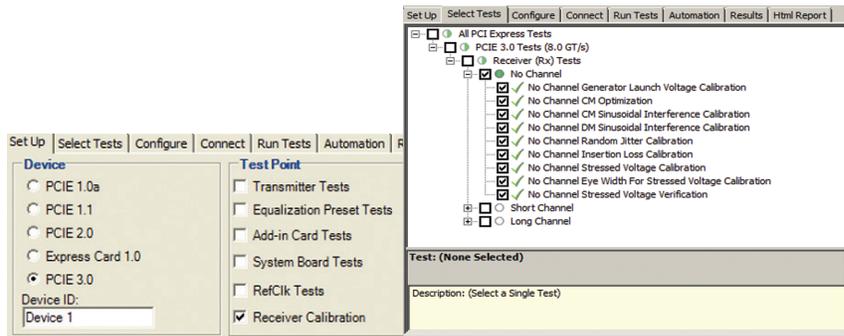


Figure 20. Configuring the type of receiver test calibration to perform.

The N5393D utilizes the PCI SIG's own Seasim simulation software to determine the target signal impairments and communicates those parameters to the instruments configured as part of the receiver test setup. The Keysight DSA90000 series oscilloscope is used to capture traces from the JBERT system setup, and that information is used by Seasim to set the calibration values of the bit error ratio tester setup.

The N5393D option 004 is provided to help automate the most rigorous step in receive testing, the calibration step. Once the equipment is calibrated, the actual receiver stress test can be performed manually or by using additional automation tools provided by Keysight and its partners. The N5393C-4FP covers automates only the calibration step. You can also reference the Keysight application note on PCIe 3.0 BASE spec receiver testing at: <http://literature.cdn.keysight.com/litweb/5990-6599EN.pdf> for additional information.

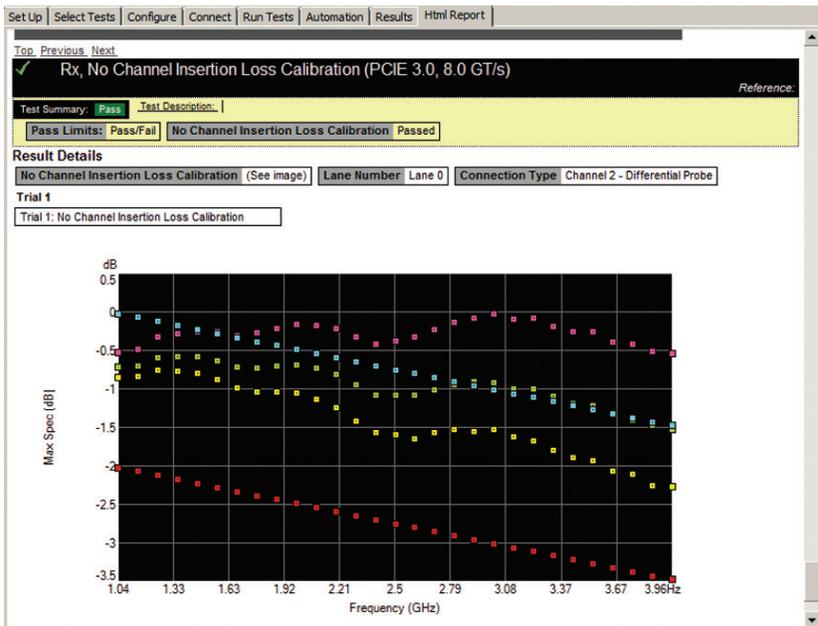


Figure 21. In the HTML test report the N5393D generates the appropriate graphical summary for each calibration parameter it configures. This gives you a traceable reference for how the tool setup and the calibration can save time when de-bugging the RX test setup.

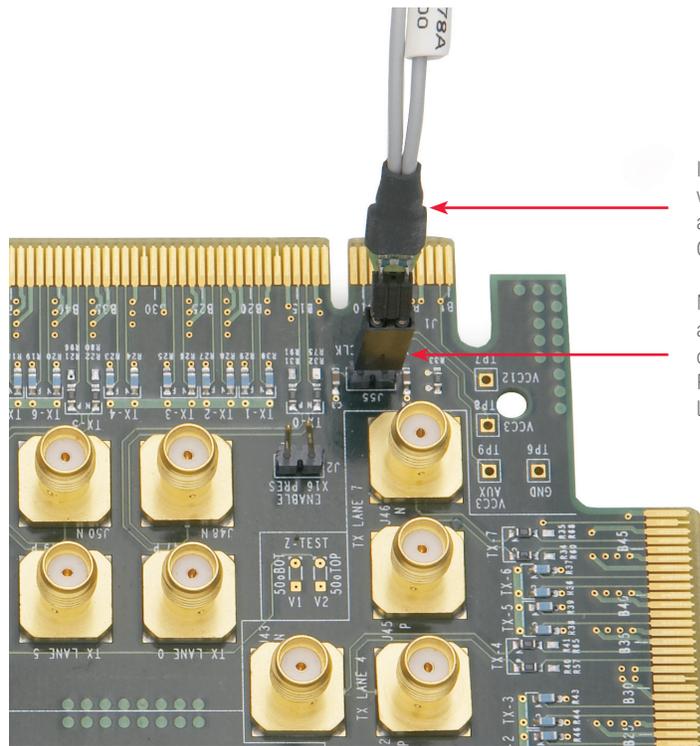
Reference Clock Measurements

The PCI Express 1.0a specification failed to specify the input bandwidth the reference clock receiver or phase jitter of the reference clock itself. This is important because jitter that lies within the loop bandwidth the receiver PLL for the reference clock will transfer onto the high speed data lines. This hole in the PCI Express specification was corrected in the 1.1 update.

The N5393D includes powerful reference clock evaluation tools including phase jitter. The PCIe 1.1 specification calls for a very specific phase jitter filter that focuses the measurement on the jitter that lies between 1.5 and 22-MHz. The filter also amplifies the jitter 3 dB (peaking) within this region. The Keysight N5393D includes proprietary filtering software (patent pending) that exactly implements the filters specified in the PCI Express specification. The N5393D also includes reference clock tests based on the PCIe 2.0 and 3.0 specification.

Utilizing Keysight's InfiniiMax 1169A high performance differential probes, or direct cabled connections, you can measure your reference clock using the PCI-SIG's Compliance Load Board or custom test fixture.

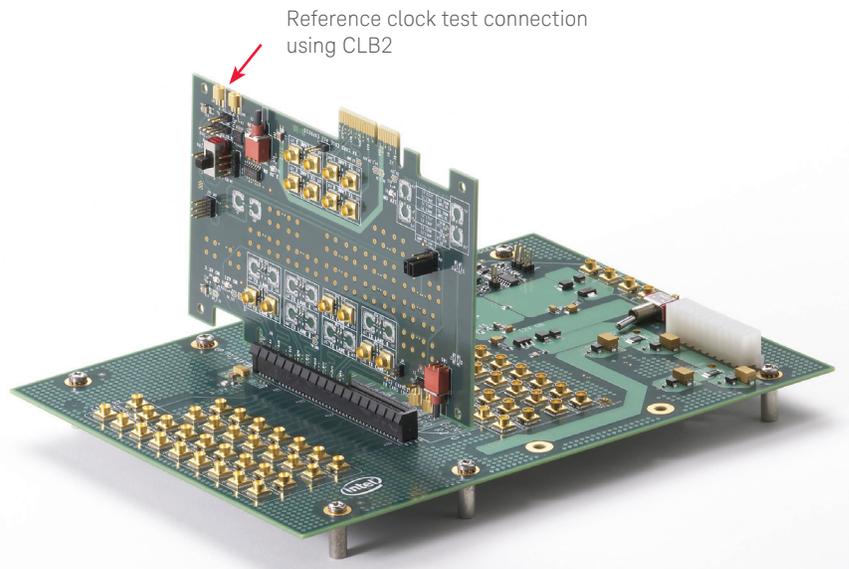
- Reference clock tests
- Phase jitter
- Rising edge rate
- Falling edge rate
- Differential input high voltage
- Differential input low voltage
- Average clock period
- Duty cycle



InfiniiMax 1169A probe with E2678A socket adapter attached to CLB

Note 2pF capacitors added to CLB to create REFCLK compliance load as per spec

Figure 22. The N5393D software includes important tests for the reference clock of your PCI Express system. This signal can be probed using the Keysight InfiniiMax 1169A probes in conjunction with the PCI-SIG's compliance load board.



Reference clock test connection using CLB2

Figure 23. This shows the CLB2 inserted into the CBB2 test fixture, representing the setup required to test add-in cards

Powerful Debugging Aids

If your device fails a test, you need to determine how it failed. To use the PCI Express electrical test software, you must install Keysight's high-speed serial data analysis software, which provides you with several powerful debugging tools. The 8b/10b decoding feature lets

you identify data-dependent errors that result in eye mask violations caused by inter-symbol interference (ISI). You can perform 8b/10b decoding to capture and display serial data synchronized with the analog view of a serial data stream (For PCIe 1.x and 2.x).



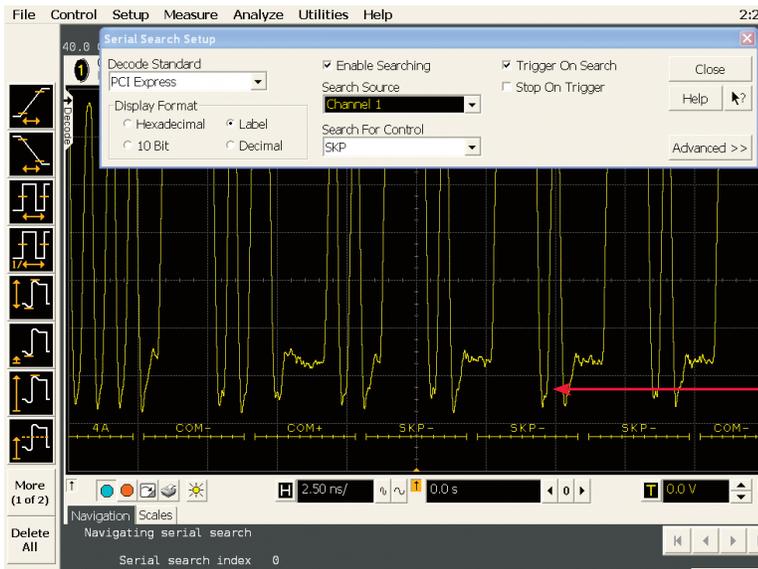
Figure 24. The 8b/10b decoded symbol information is shown below the appropriate portion of a PCI Express signal using the E2688A software.

Powerful Debugging Aids (continued)

Using the E2688A Serial Data Analysis tool you can test for illegal characters in your compliance pattern. You can also use the mask test feature to identify the specific digital patterns that caused a specific failure in the eye diagram when testing under the 1.1 specification (using a

first order PLL).

For 2.0 testing you can use a first or second order PLL for clock recovery and apply a TIE brick wall filter (included with the E2688A Series Data Analysis package) to achieve a proper clock filtering.



Problems with early silicon still persist with new PCI Express devices. Make sure yours isn't one of them. SKP characters are not allowed in the compliance pattern.

Figure 25. Check for illegal characters in the compliance pattern (such as SKP's) using the E2688A Serial Data Analysis tool.

Powerful Debugging Aids (continued)

Real Time Eye

Individual bit errors may be observed by unfolding a real time eye. To position to the first failure, stop the acquisition when failures have occurred. You may use Stop On Failure in the mask test

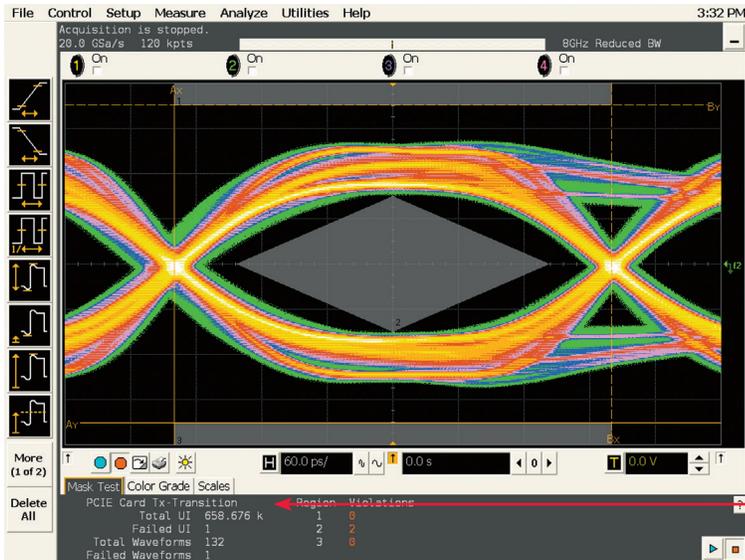
Number of failed UI: 1

Position To First Failure

Use the Navigation Tab to search for mask failures

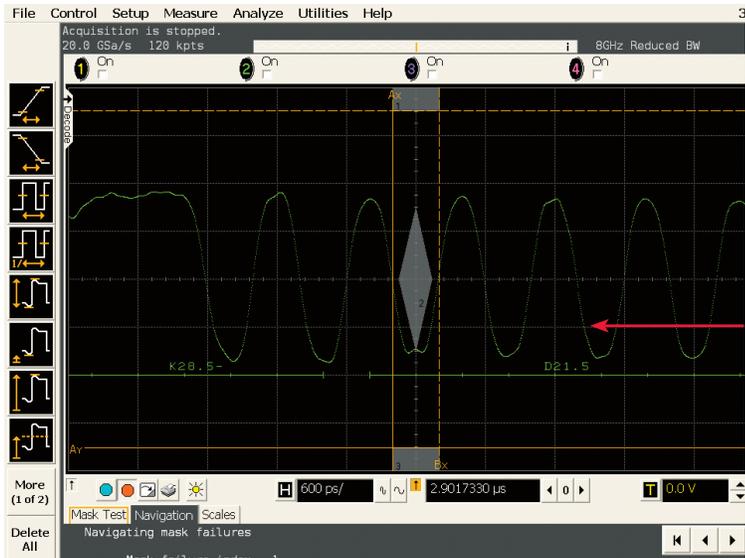
Close

Help



This eye fails after 658K UIs are analyzed

Figure 26.



Here you see the specific waveform (and 10-bit code) that caused the eye failure

Figure 27. The E2688A allows you to show the specific waveform that caused an eye diagram failure.

Measurement Requirements

The PCI Express electrical performance validation and compliance software requires the E2688A high-speed serial data analysis software, one of the PCI-SIG approved compliance test fixtures (CBB or CLB), and at least two SMA cables or InfiniiMax active differential probes. The N5393D optionally requires the InfiniiSim waveform transformation tool-set to enable to de-embedding or de-convolving of test fixture and cable losses based on user supplied

S-parameter descriptions of these structures. Some of the measurements cannot be made with the PCI-SIG compliance test fixtures and may require you to build or acquire a custom test board, assembly, or other test fixture.

To purchase the PCI Express compliance test fixtures, consult the PCI-SIG Web site and select the PCI-SIG specification order form link at: www.pcisig.com/specifications/ordering_information

| Compliance test fixture | Description |
|-------------------------|---|
| CBB | PCI Express Compliance Base Board for testing PCI Express add-in cards |
| CLB | PCI Express Compliance Load Board for testing PCI Express platforms |
| CBB2 | Gen 2 PCI Express Compliance Base Board for testing PCI Express add-in cards |
| CLB2 | Gen2 PCI Express Compliance Load Board for testing PCI Express platforms |
| CBB3 | Gen 3 PCI Express Compliance Base Board for testing PCI Express add-in cards |
| CLB3 | Gen3 PCI Express Compliance Load Board for testing PCI Express platforms |

Recommended Test Accessories

To complete your test setup, Keysight provides a wide range of cables, adapters, terminations, etc.

Note:

While the PCI-SIG does supply Gen2 test fixtures for motherboard and add-in card testing, you will need to obtain SMP cables, adapters and terminators from a vendor of your choice as the SIG does not supply them.

Table 2. Recommended test accessories

| Add-in card testing | |
|--|--|
| Model number | Description |
| | PCI-SIG Compliance Base Board (order from www.pcisig.com/specifications/ordering_information) |
| 15442A | Two SMA cables |
| | One PC power supply |
| | One power supply load for regulation |
| 1810-0118 | Six 50 Ω terminators |
| System motherboard testing | |
| | PCI-SIG Compliance Base Board (order from www.pcisig.com/specifications/ordering_information) |
| 15442A | Two SMA cables |
| 1134A or 1169A | InfiniiMax probe with socketed (E2678A) probe adapter |
| 250-1741 | Two right angle SMA adapters (f - m) |
| 1810-0118 | Six 50 Ω terminators |
| Semiconductor device testing | |
| | Customer supplied custom test fixtures with SMAs |
| 15442A | Two SMA cables |
| 1169A | One InfiniiMax probe with differential solder connection (E2677A) |
| Optional (for all types of testing) | |
| 11667B | Power splitter, DC to 26.5 GHz, 3.5 mm (f) connectors |
| 11636B | Power divider, DC to 26.5 GHz, 3.5 mm (f) connectors |
| 1250-1159 | Three SMA (m - m) adapters |
| 8493B | Coaxial attenuator (3, 6, 10, 20 or 30 dB), DC to 18 GHz, SMA connector |
| | Matched cable pair, two 90 cm (36 inch) SMA (m - m) cables propagation delay within 25 ps |
| 1810-0118 | SMA (m) 50 Ω termination |

Tests Performed

The PCI Express electrical performance validation and compliance software performs the following tests as per the PCI Express 1.0a and 1.1 electrical specifications for add-in cards and motherboard systems as documented in Section 4 of the base specification (“PHY”) and Section 4 of the card electromechanical specification (“EM”). For reference, the tests performed by the SigTest application are also noted.

For Gen2 testing coverage, the PCI-SIG decided not to create checklist, as was done for Gen1. For test coverage refer to section 4.7.2. Table 4-8 of the PCI Express 2.0 Card Electromechanical Specification.

For PCI Express 3.0, test coverage includes items listed on table 4-18 under section 4.3.3 of the PCI Express 3.0 Base Specification.

| Assertion no. | Description | Keysight PCI Express | SigTest |
|--|--|----------------------|---------|
| Transmitter tests | | | |
| PHY.3.1#26 | DC common mode voltage | Y | N |
| PHY.3.2#1 | De-emphasis on multiple bits same polarity in succession | Y | N |
| PHY.3.2#2 | Transition bit voltage | Y | N |
| PHY.3.3#1 | Transmitter eye diagram | Y | N |
| PHY.3.3#2 | Unit interval without SSC variations | Y | N |
| PHY.3.3#3 | Minimum D+/D- output rise/fall time | Y | N |
| PHY.3.3#4 | Jitter median to max deviation | Y | N |
| PHY.3.3#5 | Maximum RMS AC common mode voltage | Y | N |
| PHY.3.3#9 | Minimum eye width | Y | N |
| Receiver tests | | | |
| PHY.3.4#1 | Minimum receiver eye diagram | Y* | N |
| PHY.3.4#2 | AC peak common mode input voltage | Y* | N |
| PHY.3.4#6 | Jitter median to max deviation input | Y* | N |
| System board (connector) tests | | | |
| EM.4#4 | Minimum jitter | Y | Y |
| EM.4#20 | Transmitter path eye diagram | Y | Y |
| Reference clock (connector) tests | | | |
| PHY.3.3#2 | Phase jitter | Y | N/A* |
| PHY.3.3#1 | Rising edge rate | Y | N/A |
| PHY.3.3#1 | Falling edge rate | Y | N/A |
| PHY.3.3#4 | Differential input high voltage | Y | N/A |
| PHY.3.3#4 | Differential input low voltage | Y | N/A |
| PHY.3.3#9 | Average clock period | Y | N/A |
| PHY.3.2#2 | Duty cycle | Y | N/A |
| Add-in card (connector) tests | | | |
| EM.4#13 | Minimum jitter | Y | Y |
| EM.4#19 | Transmitter path eye diagram | Y | Y |

Note:

* Receiver tests provided by the Keysight PCI Express software are listed under the PCIe 1.x or 2.0 test tabs do not validate the receiver’s tolerance or ability to correctly receive data. They validate the signal at the receiver against specified tolerances

Ordering Information

PCI Express 1.x and 2.x transmitter testing

| License type | | Infiniium Z-Series | Infiniium S-Series | Infiniium 90000 Series | Infiniium 9000 Series |
|--------------|-------------------|--------------------|--------------------|------------------------|-----------------------|
| Fixed | Factory-installed | N5393D-3FP | N5393E-3FP | Option 022 | – |
| | User-installed | N5393D-3FP | N5393E-3FP | N5393D-3NL | N5393E-3NL |
| Floating | Transportable | N5393D-3TP | N5393E-3TP | N5393D-3TP | N5393E-3TP |
| | Server-based | N5435A-009 | | | |

Upgrade to PCIe 3.0 transmitter testing

| License type | | Infiniium Z-Series | Infiniium S-Series | Infiniium 90000 Series | Infiniium 9000 Series |
|--------------|-------------------|--------------------|--------------------|------------------------|-----------------------|
| Fixed | Factory-installed | – | – | – | – |
| | User-installed | N5393D-2FP | – | N5393D-2NL | – |
| Floating | Transportable | – | – | – | – |
| | Server-based | – | | | |

PCIe 3.x transmitter testing

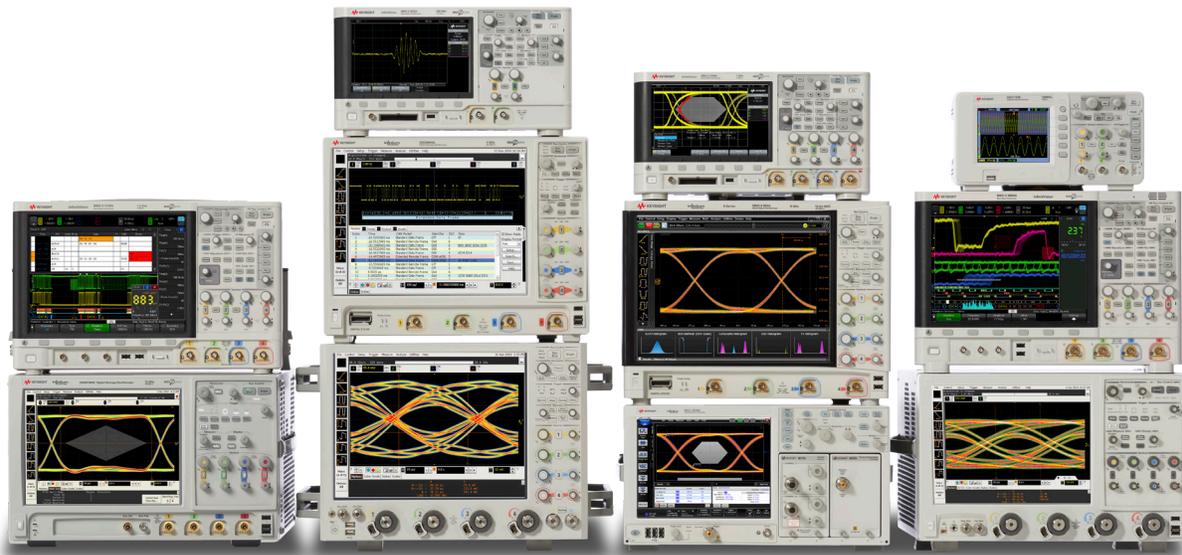
| License type | | Infiniium Z-Series | Infiniium S-Series | Infiniium 90000 Series | Infiniium 9000 Series |
|--------------|-------------------|--------------------|--------------------|------------------------|-----------------------|
| Fixed | Factory-installed | N5393D-1FP | – | Option 044 | – |
| | User-installed | N5393D-1FP | – | N5393D-1NL | – |
| Floating | Transportable | N5393D-1TP | – | N5393D-1TP | – |
| | Server-based | N5435A-040 | | | |

PCIe 3.0 BASE spec receiver test calibration

| License type | | Infiniium Z-Series | Infiniium S-Series | Infiniium 90000 Series | Infiniium 9000 Series |
|--------------|-------------------|--------------------|--------------------|------------------------|-----------------------|
| Fixed | Factory-installed | N5393D-4FP | – | – | – |
| | User-installed | N5393D-4FP | – | N5393D-4NL | – |
| Floating | Transportable | N5393D-4TP | – | N5393D-4TP | – |
| | Server-based | – | | | |

PCIe switch matrix support

| License type | | Infiniium Z-Series | Infiniium S-Series | Infiniium 90000 Series | Infiniium 9000 Series |
|--------------|-------------------|--------------------|--------------------|------------------------|-----------------------|
| Fixed | Factory-installed | N5393D-7FP | N5393E-7FP | Option 705 | – |
| | User-installed | N5393D-7FP | N5393E-7FP | N5393D-7NL | N5393E-7NL |
| Floating | Transportable | N5393D-7TP | N5393E-7TP | N5393D-7TP | N5393E-7TP |
| | Server-based | N5435A-705 | | | |



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